N-channel TrenchMOS logic level FET

Rev. 03 — 7 April 2010

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

#### Suitable for logic level gate drive sources

■ Suitable for thermally demanding environments due to 175 ℃ rating

### **1.3 Applications**

- 12 V loads
- Automotive systems

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- General purpose power switching
- Motors, lamps and solenoids

### 1.4 Quick reference data

ck reference da	ta					
rameter	Conditions		Min	Тур	Max	Unit
ain-source Itage	T <sub>j</sub> ≥ 25 ℃; T <sub>j</sub> ≤ 175 °C		-	-	30	V
ain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 ℃; see <u>Figure 1</u> ; see <u>Figure 4</u>	<u>[1]</u>	-	-	75	A
al power sipation	$T_{mb} = 25 $ °C; see <u>Figure 2</u>		-	-	105	W
ristics						
ain-source -state sistance	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ C}; \text{ see } Figure 12;$ see Figure 13		-	4.9	7	mΩ
	$V_{GS} = 10 \text{ V}; \text{ I}_D = 25 \text{ A};$ T <sub>j</sub> = 25 °C		-	4	6	mΩ
a	edness	T <sub>j</sub> = 25 °C	$T_j = 25 $ °C	$T_j = 25 $ °C	$T_j = 25 $ °C	$T_j = 25 \text{ C}$

Avalanche ruggedness



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Table 1.	Quick reference data continued						
Symbol	Parameter	Conditions	Ν	Min	Тур	Max	Unit
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 75 \text{ A};  \text{V}_{\text{sup}} \leq 30  \text{V}; \\ R_{\text{GS}} &= 50  \Omega;  \text{V}_{\text{GS}} = 5  \text{V}; \\ T_{j(\text{init})} &= 25  \mathbb{C}; \text{ unclamped} \end{split} $	-		-	198	mJ
Dynamic characteristics							
$Q_{GD}$	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 24 \text{ V}; \text{ see } Figure 14$	-		12.4	-	nC

[1] Continuous current is limited by package.

### 2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	
3	S	source		
4	G	gate		G-(
mb	D	mounting base; connected to drain	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	mb/798 S1 S2 S3
			SOT669 (LFPAK)	

### 3. Ordering information

Table 3.	Ordering in	formation		
Type num	ber	Package		
		Name	Description	Version
BUK9Y07-3	30B	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

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### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 ℃; T <sub>j</sub> ≤ 175 ℃		-	-	30	V
V <sub>DGR</sub>	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	-	30	V
V <sub>GS</sub>	gate-source voltage			-15	-	15	V
I <sub>D</sub>	drain current	$T_{mb} = 25 $ °C; $V_{GS} = 5 $ V; see <u>Figure 1</u> ; see <u>Figure 4</u>	<u>[1]</u>	-	-	75	А
		$T_{mb}$ = 100 °C; V <sub>GS</sub> = 5 V; see <u>Figure 1</u>		-	-	63	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; t <sub>p</sub> ≤ 10 µs; pulsed; see Figure 4		-	-	356	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 ℃; see <u>Figure 2</u>		-	-	105	W
T <sub>stg</sub>	storage temperature			-55	-	175	C
Tj	junction temperature			-55	-	175	C
Source-drain	n diode						
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	<u>[1]</u>	-	-	75	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ C$		-	-	356	А
Avalanche ru	uggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:ld} \begin{array}{l} I_D = 75 \text{ A}; \ V_{sup} \leq 30 \text{ V}; \ R_{GS} = 50 \ \Omega; \\ V_{GS} = 5 \text{ V}; \ T_{j(init)} = 25 \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $		-	-	198	mJ
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	see Figure 3	<u>[2][3][4][</u> <u>5]</u>	-	-	-	J

[1] Continuous current is limited by package.

[2] Maximum value not quoted. Repetitive rating defined in avalanche rating figure.

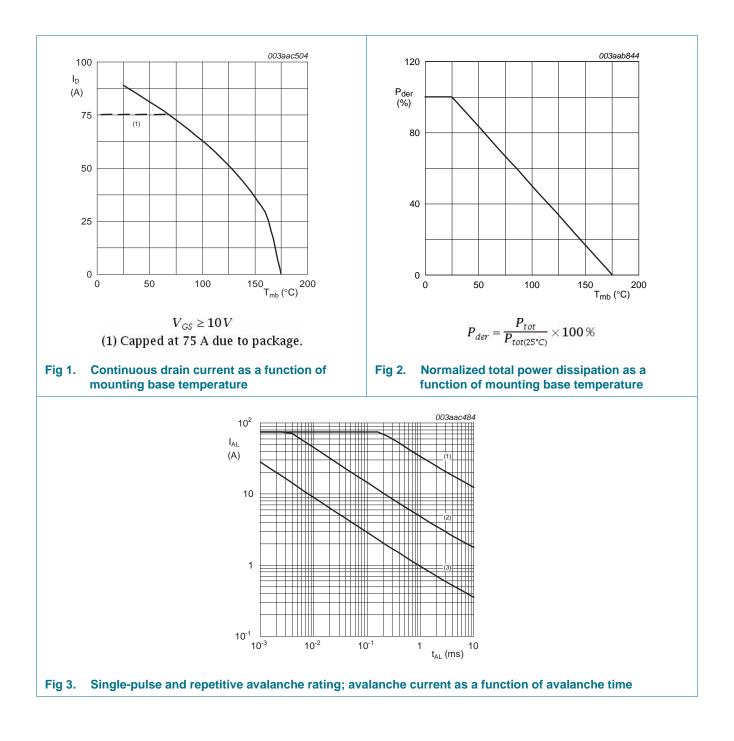
[3] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[4] Repetitive avalanche rating limited by an average junction temperature of 170  $^{\circ}$ C.

[5] Refer to application note AN10273 for further information.

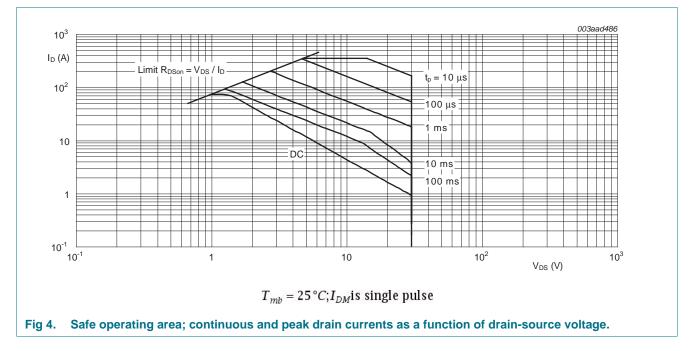
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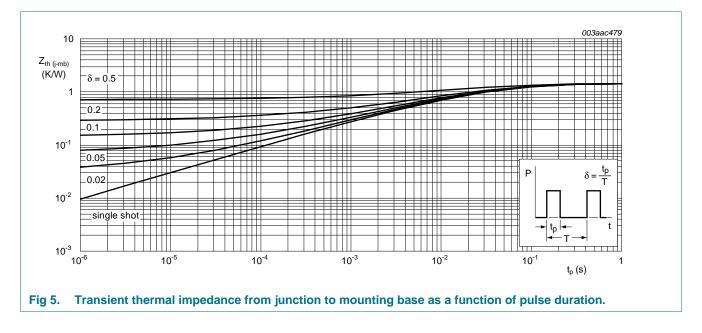
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### 5. Thermal characteristics

#### Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see <u>Figure 5</u>	-	-	1.42	K/W



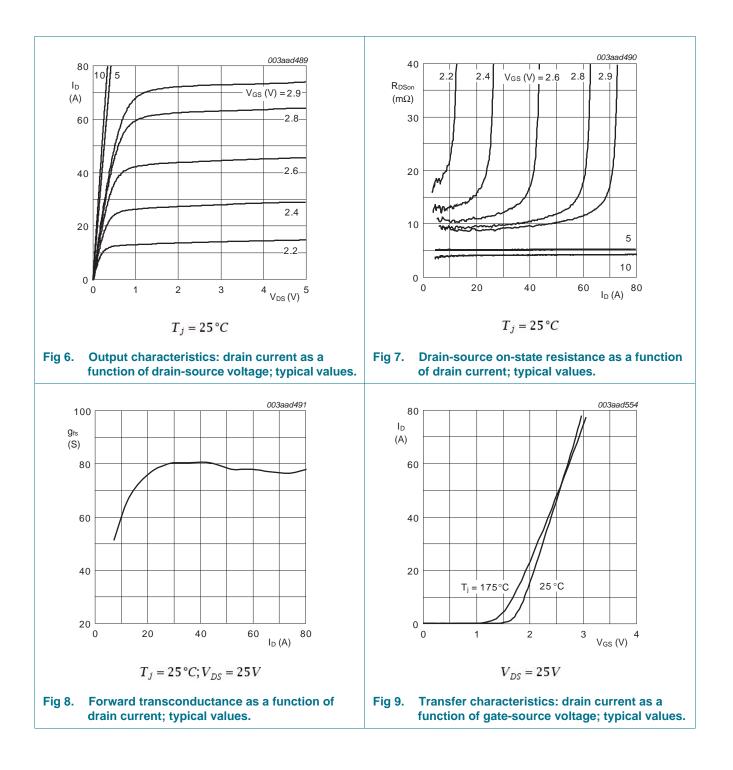
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### 6. Characteristics

	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 0.25 mA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	27	-	-	V
breakdown voltage		$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	30	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ C};$ see <u>Figure 10</u> ; see <u>Figure 11</u>	1.1	1.5	2	V
/ <sub>GSth</sub> gate-source thre voltage	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ C};$ see <u>Figure 10</u> ; see <u>Figure 11</u>	0.5	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ C};$ see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	2.3	V
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 30 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.02	1	μΑ
		$V_{DS}$ = 30 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500	μΑ
I <sub>GSS</sub> gate leakage curren	gate leakage current	$V_{DS}$ = 0 V; $V_{GS}$ = 15 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{DS}$ = 0 V; $V_{GS}$ = -15 V; $T_j$ = 25 °C	-	2	100	nA
R <sub>DSon</sub> drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ C};$ see <u>Figure 12</u> ; see <u>Figure 13</u>	-	4.9	7	mΩ	
		$V_{GS}$ = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C	-	-	8	mΩ
		$V_{GS} = 5 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \text{ T}_{j} = 175 ^{\circ}\text{C};$ see Figure 12; see Figure 13	-	-	13.3	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>i</sub> = 25 °C	-	4	6	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 5 \text{ V};$	-	28.1	-	nC
Q <sub>GS</sub>	gate-source charge	see Figure 14	-	6.7	-	nC
Q <sub>GD</sub>	gate-drain charge		-	12.4	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; \text{ V}_{DS} = 25 \text{ V}; \text{ f} = 1 \text{ MHz};$	-	1580	2500	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 $ °C; see Figure 15	-	500	600	pF
C <sub>rss</sub>	reverse transfer		-	225	308	pF
	capacitance		-			•
t <sub>d(on)</sub>	capacitance turn-on delay time	$V_{DS}$ = 25 V; $R_L$ = 1 $\Omega$ ; $V_{GS}$ = 5 V;	-	25.9	-	ns
	•	$V_{\text{DS}} = 25 \text{ V}; \text{ R}_{\text{L}} = 1 \Omega; \text{ V}_{\text{GS}} = 5 \text{ V};$ $\text{R}_{\text{G}(\text{ext})} = 10 \Omega$	-			•
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub>	turn-on delay time		-	25.9	-	ns
<sup>t</sup> r <sup>t</sup> d(off)	turn-on delay time rise time		-	25.9 64.5	-	ns ns
t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	turn-on delay time rise time turn-off delay time		-	25.9 64.5 82.3	-	ns ns ns
t <sub>r</sub> t <sub>d(off)</sub> tf Source-d	turn-on delay time rise time turn-off delay time fall time		-	25.9 64.5 82.3	-	ns ns ns
t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	turn-on delay time rise time turn-off delay time fall time rain diode	$R_{G(ext)} = 10 \Omega$ I <sub>S</sub> = 25 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C;	-	25.9 64.5 82.3 64.8	- - -	ns ns ns ns

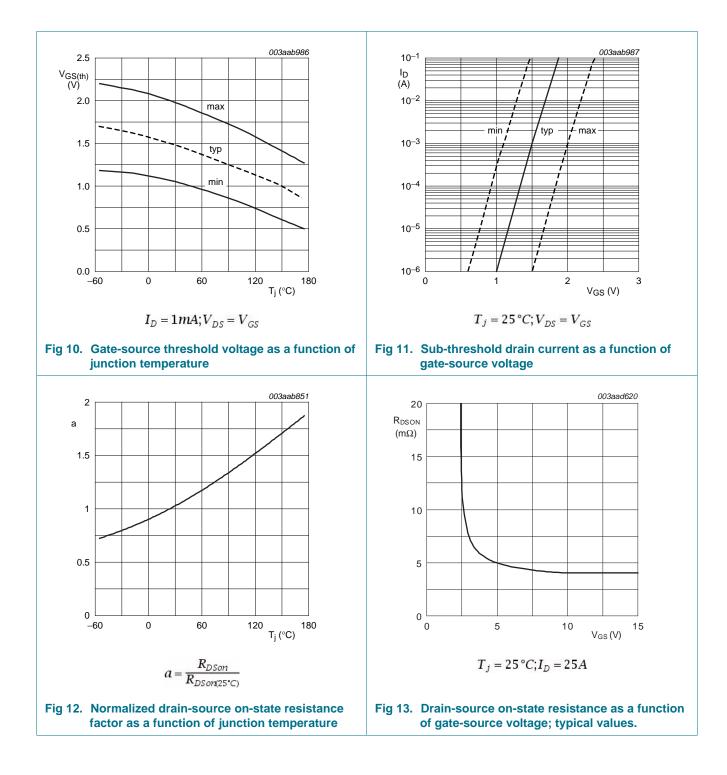
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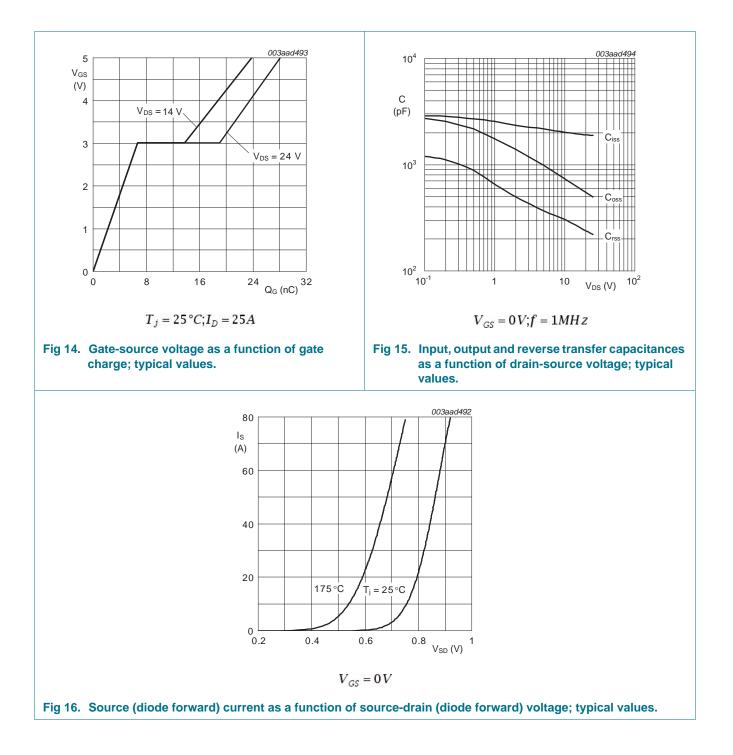


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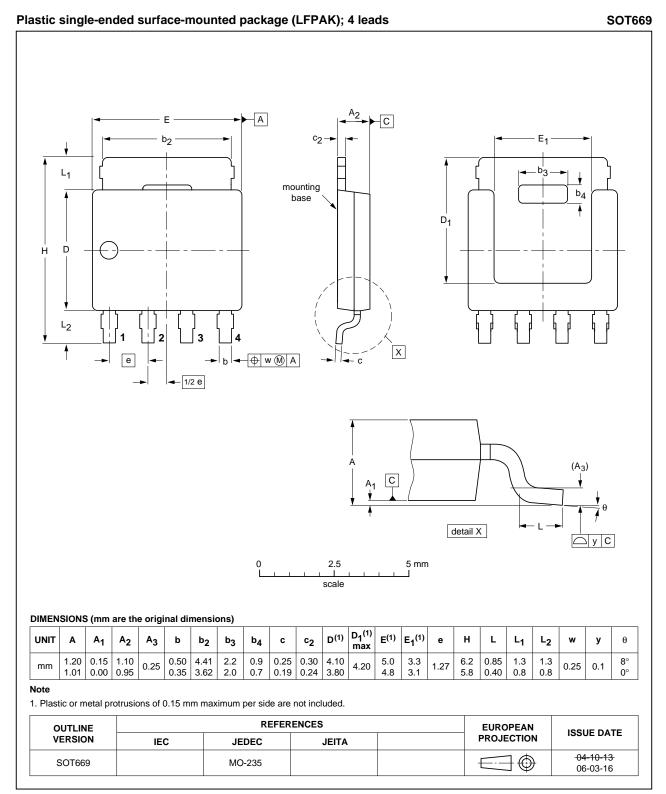


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## BUK9Y07-30B

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### 7. Package outline



#### Fig 17. Package outline SOT669 (LFPAK)

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### 8. Revision history

Table 7. Revision his	story			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9Y07-30B_3	20100407	Product data sheet	-	BUK9Y07-30B_2
Modifications:	<ul> <li>Status char</li> </ul>	nged from objective to pro	duct.	
BUK9Y07-30B_2	20100215	Objective data sheet	-	BUK9Y07-30B_1

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### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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